

**Notice of References Cited**

Application/Control No.

10/080,884

Applicant(s)/Patent Under

Reexamination

KIM ET AL.

Examiner

DuyVu n Deo

Art Unit

1765

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0117731	08-2002	Kim et al.	257/510
	B	US-6,140,208	10-2000	Agahi et al.	438/437
	C	US-6,037,018	03-2000	Jang et al.	427/579
	D	US-6,180,493	01-2001	Chu, Chih-Hsun	438/437
	E	US-6,251,735	06-2001	Lou, Chine-Gie	438/296
	F	US-6,461,937	10-2002	Kim et al.	438/431
	G	US-6,046,487	04-2000	Benedict et al.	257/510
	H	US-5,190,889	03-1993	Poon et al.	438/437
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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